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SERIAL NUMBER 10/784,411	FILING DATE 02/23/2004  RULE	CLASS 117	GROUP ART UNIT 1722	ATTORNEY DOCKET NO. JG-SU- 5198/500577.20056	
<b>APPLICANTS</b>  Jun Furukawa, Tokyo, JAPAN;  Kazunari Kurita, Tokyo, JAPAN; Kazuhiro Harada, Tokyo, JAPAN;  <b>** CONTINUING DATA *****</b>  <b>** FOREIGN APPLICATIONS *****</b>  <b>IF REQUIRED, FOREIGN FILING LICENSE GRANTED</b> <b>** 08/26/2004</b>					
Foreign Priority claimed <input type="checkbox"/> yes <input checked="" type="checkbox"/> no 35 USC 119 (a-d) conditions <input type="checkbox"/> yes <input checked="" type="checkbox"/> no <input type="checkbox"/> Met after met Allowance Verified and Acknowledged		STATE OR COUNTRY JAPAN	SHEETS DRAWING 22	TOTAL CLAIMS 13	INDEPENDENT CLAIMS 5
<b>ADDRESS</b> 026418 REED SMITH, LLP ATTN: PATENT RECORDS DEPARTMENT 599 LEXINGTON AVENUE, 29TH FLOOR NEW YORK , NY 10022-7650					
<b>TITLE</b> Method of identifying defect distribution in silicon single crystal ingot					
FILING FEE  RECEIVED 1072	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:		<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees ( Filing ) <input type="checkbox"/> 1.17 Fees ( Processing Ext. of time ) <input type="checkbox"/> 1.18 Fees ( Issue )		

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